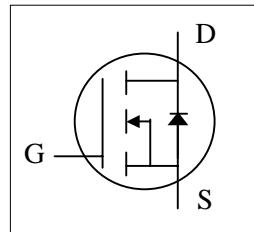




- ▼ Simple Drive Requirement
- ▼ Lower On-resistance
- ▼ Lower Gate Charge
- ▼ RoHS Compliant & Halogen-Free

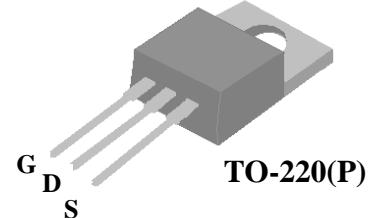


BV_{DSS}	60V
$R_{DS(ON)}$	3.5mΩ
I_D	161A

Description

AP9992A series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications

The TO-220 package is widely preferred for all commercial-industrial through hole applications. The low thermal resistance and low package cost contribute to the worldwide popular package.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	+20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current (Chip)	161	A
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^3$	120	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	102	A
I_{DM}	Pulsed Drain Current ¹	300	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	166	W
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	2	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	0.75	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient	62	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=40\text{A}$	-	-	3.5	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2	-	5	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=40\text{A}$	-	80	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=48\text{V}, V_{\text{GS}}=0\text{V}$	-	-	25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge	$I_{\text{D}}=40\text{A}$	-	92	147	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=48\text{V}$	-	20	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	39	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=30\text{V}$	-	23	-	ns
t_r	Rise Time	$I_{\text{D}}=40\text{A}$	-	82	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$	-	47	-	ns
t_f	Fall Time	$V_{\text{GS}}=10\text{V}$	-	83	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	5500	8800	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	870	-	pF
C_{rss}	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	350	-	pF
R_g	Gate Resistance	$f=1.0\text{MHz}$	-	2	4	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=40\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.3	V
t_{rr}	Reverse Recovery Time	$I_{\text{S}}=10\text{A}, V_{\text{GS}}=0\text{V},$	-	60	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	120	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Package limitation current is 120A.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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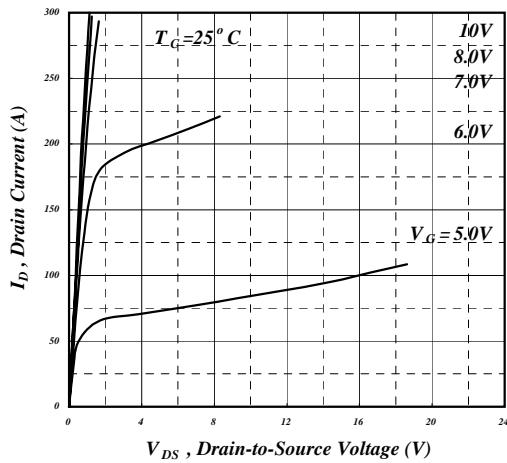


Fig 1. Typical Output Characteristics

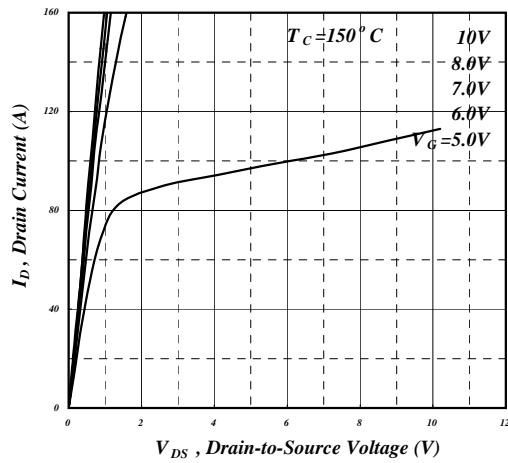


Fig 2. Typical Output Characteristics

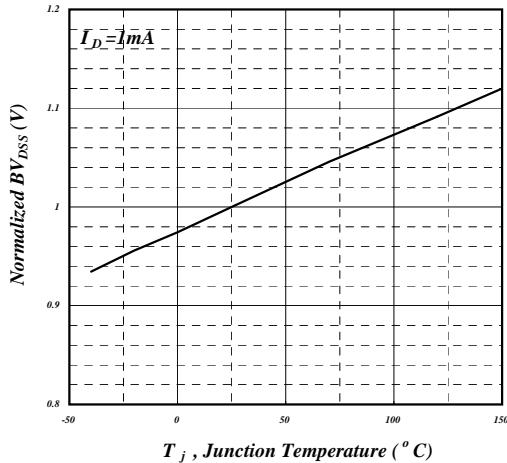
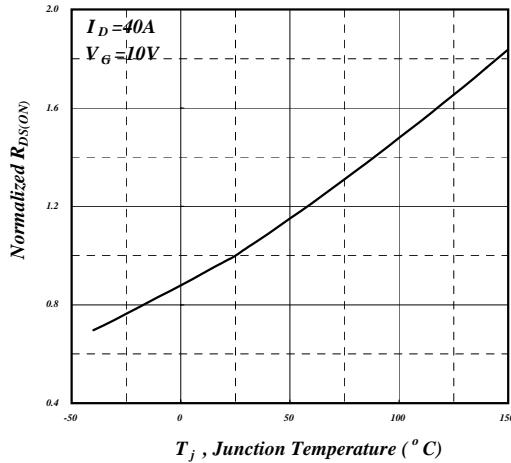
Fig 3. Normalized BV_{DSS} v.s. Junction Temperature

Fig 4. Normalized On-Resistance v.s. Junction Temperature

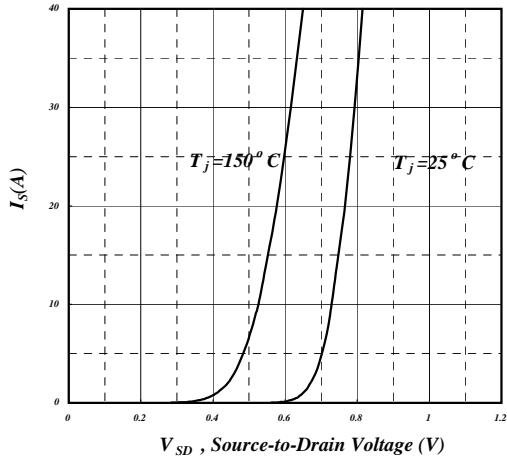


Fig 5. Forward Characteristic of Reverse Diode

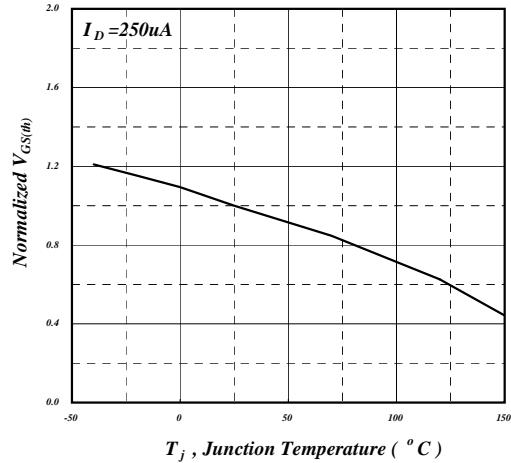


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

